

**Notice of References Cited**

Application/Control No.

10/016,896

Applicant(s)/Patent Under  
Reexamination  
SUN ET AL.

Examiner

Thanh T. Nguyen

Art Unit

2813

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,316,349	11-2001	Kim et al.	216/71
	B	US-6,335,249	01-2002	Thei et al.	438/296
	C	US-6,337,244	01-2002	Prall et al.	438/257
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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